Special Subject Book January 2000

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Thermal Resistance Theory and Practice

 $R_{
m thj-a}$

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SMD Packages



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Never stop thinking

Edition January 2000

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11

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Thermal Resistance - Theory and Practice **Contents**

Introduction 4
SMD-Package Properties for Power Applications
Using a Printed Circuit Board as a Heat Sink
Static Properties
Dynamic Properties
Finite Element Method (FEM) 13
Determining the Static Heat Resistance
Measuring the <i>R</i> _{thj-a} in the Real Application
Determining the Dynamic Heat Resistance
Summary
Package and Thermal Information



Power-SMD applications or what's the size of the heat sink ?

More and more frequently, modern SMD-component users (Surface Mounted Devices) ask the question, "What's the size of the heat sink ?" The reason: The trend from through-hole packages to low-cost SMD-applications is marked by the improvement of chip technologies.

"Silicon instead of heat sink" is therefore possible in many cases. The printed circuit board (PCB) itself becomes the heat sink. As many applications today use PCBs assembled with SMDtechnology, the emphasis is on Power-ICs in SMD packages mounted on single-sided PCBs laminated on one side. Pricing pressure demands simple processes and lowest-cost solutions. This report describes a solution.

SMD-Package Properties for Power Applications

There are two basic groups of packages:

Heat Sink packages are the first group. The heat sink (chip carrier - lead frame) is soldered directly to the PCB. The thermal resistance of this packages between chip and heat sink is called R_{thj-c} (junction-case) and has low values.

Thermal Enhanced Leadframes constitute the second group of packages. Metal bridges are connected between the chip carrier (lead frame) and the pins. From the outside, this package looks identical to standard components because the plastic molding compound conceals these details. **Figure 1** shows both types of packages with the examples P-TO252-3-1 (D-Pack) and P-DSO-14-4 (3 center pins each per side of the cooling path). The internal structure is described in more detail in this report and can be seen in **Figure 11**.



Figure 1 Heat Sink - vs. Thermal Enhanced Package Types

Using a printed circuit board as a heat sink ? How do I calculate that ? How big does my heat sink need to be ? Which size do we need ?

In earlier fabrications, a solid heat sink was either screwed or clamped to the power package. It was easy to calculate the thermal resistance from the geometry of the heat sink.

In SMD-technology, this calculation is much more difficult because the heat path must be evaluated: chip (junction) - lead frame - case or pin - footprint -PCB materials (basic material, thickness of the laminate) - PCB volume - surroundings. As the layout of the PCB is a main contributor to the result, a new technique must be applied. The Appendix proivdes thermal data for all packages listed in **Table 1**.

Let us start with some theoretical considerations:

Static Properties

To facilitate discussion of the static properties of a Power IC (PIC), the internal structure of a PIC and its method of mounting on a PCB or heat sink is illustrated in **Figure 2**. The PIC consists of a chip mounted on a chip carrier or lead frame, and held by solder or bonding adhesive. The lead frame consists of a high-conductivity material such as copper, and can have a

Package	Heat Sink / Pin		
P-DSO-8-1	-		
P-DSO-14-4	Pin 3-5; 10-12		
P-DSO-16-1	-		
P-DSO-20-1	-		
P-DSO-20-6	Pin 4-7; 14-17		
P-DSO-24-3	Pin 5-8; 17-20		
P-DSO-28-6	Pin 6-9; 20-23		
P-DSO-20-10	Tab		
P-DSO-36-10	Tab		
SCT-595-5-1	Pin 2; 5		
SOT-223-4-2	Tab or Pin 4		
P-TO252-3-1 (D-Pack)	Tab		
P-TO263-5-1	Тар		

Table 1 The Most Important SMD-Packages



Figure 2 Internal Structure of a PIC and Method of Mounting on a Heat Sink



R_{thj-a}

Figure 3 Static Equivalent Circuit for the Structure shown in Figure 2 thickness of several millimeters. The associated static equivalent circuit is shown in **Figure 3**. The following analogies with electrical quantities have been used:

- The power dissipation P_V occurring close to the chip surface is symbolized by a current source.
- The thermal resistances are represented by ohmic resistors. The "resistance" network is essentially a serial connection to the ambient temperature. As a first approximation, the parallelconnected thermal resistance of the molding (broken lines) can be neglected in power packages.
- The ambient temperature is represented by a voltage source.

In accordance with the analogy, the thermal current $P_V = Q/t$ can now be calculated from the "thermic Ohm's law" $V = I \cdot R$ as $T_j - T_a = P_V \cdot R_{thj-a}$.

For the purpose of discussing the application as a whole, the function $P_V = f(T_a)$ is of practical interest. One obtains:

 $P_{\rm V}$ = - $T_{\rm a}$ / $R_{\rm thj-a}$ + $T_{\rm j}$ / $R_{\rm thj-a}$. This is a descending straight line of gradient -1 / $R_{\rm thj-a}$ with its zero at $T_{\rm j}$.

In Figure 4, this function is shown for the P-DSO-14-4 Package (Thermal Enhanced Power Package) mounted on the standard application board. From this function, the user can derive the permissible power dissipation directly for any ambient temperature. At $T_a = 85 \text{ °C}$, for example, the permissible dissipation is approxi-mately 0.7 W. The exact value can be calculated from the equation $P_{V} = (T_{i} - T_{amax}) / R_{thi-a} =$ 65 K / 92 K/W = 0.7 W. It should be noted that in the data sheets of the PICs the power dissipation is given as a function of the package (case) temperature $T_{\rm C}$, because the applicationspecific thermal resistances are not known to the manufacturer. This function, like the previous one, is a descending straight line. The slope now has the value 1 / $R_{\text{thi-c}}$. The zero remains at T_{i} . As an example, this function is presented in Figure 5 for the P-TO252-3-1 Package. The new P-TO252-3-1 package has a thermal resistance of max. 4 K/W and is unique in the small size of its base area when compared with packages of equivalent performance (PCB board area). At approximately 30 °C, the permissible power dissipation is 30 W. Higher power dissipation is prevented by intervention of the chip-internal current limiters. For this reason, the value for power dissipation at lower temperatures remains constant.



Figure 4 Permissible Power Dissipation of the P-DSO-14-4 Package Mounted on a PCB with 300 mm² Cooling Area, as a Function of Ambient Temperature



Figure 5

e 5 Permissible Power Dissipation of the P-TO252-3-1 as a Function of the Package (Case) Temperature

Dynamic Properties

As mentioned earlier, the thermal behavior of PICs changes when dynamic phenomena are considered (pulse power operation). This behavior can be described in terms of thermal capacity $C_{\rm th}$, which is directly proportional to the relevant volume V (in cm³), to the density ρ (in g/cm³) of the material and to a proportionality factor of the specific heat c in Ws/g • K. The applicable equation is: $C_{\rm th} = c \cdot \rho \cdot V = m \cdot c$ This means: The thermal capacity of a body of mass $m = \rho \cdot V$ corresponds to the quantity of heat

needed to heat the body by 1 °C. To calculate the temperature change ΔT it is necessary to use the quantity-of-charge equation for a capacitance C. The equation is: $V \bullet C = I \bullet t = Q$ By analogy, the quantity-of-heat equation is: $\Delta T \bullet C_{\rm th} = P \bullet t = Q$ This means: Just as the current I = Q/t represents a transport of charge per unit of time, the power dissipation P represents the transport of thermal energy per unit of time. Consequently:

 $\Delta T = \frac{P \cdot t}{t}$

The equivalent circuit of the P-TO263-7-3 power package, with the thermal capacities added, is shown in **Figure 6**. The thermal capacities calculated from the material and the volume are shown in parallel with the thermal resistances.

When calculating the components of a network it is necessary to know the thickness d, the crosssectional area A and the thermal conductivity L in W/m • K, in order to obtain the appropriate thermal resistance R_{th} . The formula is:

$$R_{\rm th} = \frac{d}{L \cdot A} \left[\frac{\mathsf{K}}{\mathsf{W}} \right]$$



Figure 6 Thermal Equivalent Circuit of the P-TO263-7-3 Package (Simplified)



Footprint



Figure 7 Outline Drawing of the P-TO263-7-3 Power Package

To calculate the thermal capacity C_{th} , it is necessary to know the volume $V = d \cdot A$, the specific weight ρ in g/cm3 and the specific thermal capacity c in Ws/g \cdot K.

The thermal capacity C_{th} is calculated from: $C_{\text{th}} = m \cdot c$ (Ws/T). The package dimensions are shown in **Figure 7**. Table 2 lists all the importantparametric data of theP-TO263-7-3 package.

Parameters for the Chip	Symbol	Value	Dimension
Area	A_{D}	5	mm²
Thickness	$d_{ m D}$	360	μm
Thermal conductivity of silicon	$L_{ m Si}$	150	W/m•K
Thermal resistance of chip	$R_{ m thD}$	0.48	K/W
Specific weight of silicon	$ ho_{Si}$	2.33	g/cm ³
Mass of chip	m _D	4.2	mg
Spec, thermal capacity of Si	c_{Si}	approx. 0.7	Ws/g•K
Thermal capacity of chip	$C_{ m thD}$	approx. 3	mWs/K
Thermal time constant of chip	$ au_{D}$	approx. 1.5	ms
Parameters for the Heat Slug	Symbol	Value	Dimension
Parameters for the Heat Slug Area (effective area of 64 mm²)	Symbol A _{HS}	Value 14	Dimension mm ²
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness	Symbol A _{HS} d _{HS}	Value 14 1.27	Dimension mm ² mm
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness Thermal conductivity of cooper	Symbol A _{HS} d _{HS} L _{Cu}	Value 14 1.27 384	Dimension mm ² mm W/m•K
Parameters for the Heat SlugArea (effective area of 64 mm²)ThicknessThermal conductivity of cooperThermal resistance of heat slug	Symbol A _{HS} d _{HS} L _{Cu} R _{thHS}	Value 14 1.27 384 0.24	Dimension mm ² mm W/m•K K/W
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness Thermal conductivity of cooper Thermal resistance of heat slug Specific weight of cooper	Symbol A_{HS} d_{HS} L_{Cu} R_{thHS} ρ_{Cu}	Value 14 1.27 384 0.24 8.93	Dimension mm ² mm W/m•K K/W g/cm ³
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness Thermal conductivity of cooper Thermal resistance of heat slug Specific weight of cooper Mass of heat slug	Symbol A _{HS} d _{HS} L _{Cu} R _{thHS} ρ_{Cu} m _{HS}	Value 14 1.27 384 0.24 8.93 0.8	Dimension mm ² mm W/m•K K/W g/cm ³ g
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness Thermal conductivity of cooper Thermal resistance of heat slug Specific weight of cooper Mass of heat slug Spec, thermal capacity of Cu	Symbol A_{HS} d_{HS} L_{Cu} R_{thHS} ρ_{Cu} m_{HS} C_{Cu}	Value 14 1.27 384 0.24 8.93 0.8 0.385	Dimension mm ² mm W/m•K K/W g/cm ³ g Ws/g•K
Parameters for the Heat Slug Area (effective area of 64 mm²) Thickness Thermal conductivity of cooper Thermal resistance of heat slug Specific weight of cooper Mass of heat slug Spec, thermal capacity of Cu Thermal capacity of heat slug	Symbol A_{HS} d_{HS} L_{Cu} R_{thHS} ρ_{Cu} m_{HS} c_{Cu} C_{thHS}	Value 14 1.27 384 0.24 8.93 0.8 0.385 310	Dimension mm ² mm W/m•K K/W g/cm ³ g Us/g•K mWs/g•K

Table 2 Parametric Data of the P-TO263-7-3



The die bond and molding components have been omitted from this discussion because they do not significantly influence the calculation of R_{thj-c} . For reference, these data are listed here:

- $R_{\rm thDB} = 0.01$ to 0.1 K/W;
- $C_{\text{thDB}} = 0.1 \text{ to } 0.5 \text{ mWs/K};$
- $\tau_{\rm DB} = 1$ to 50 ms;
- $R_{\rm thM} = 100 \, \text{K/W};$
- $C_{\text{thM}} = 0.64 \text{ Ws/K}$ and
- $\tau_{\rm M} = 64 \, {\rm s.}$

(Die Bond = index: DB; molding = index: M) The time constance of the die bond is smaller than that of the chip by two orders of magnitude and can, thus, be neglected. The thermal resistance R_{thM} of the molding is even three orders of magnitude bigger than that of the chip and that of the heat slug, and, being in parallel, can be neglected also.

Pulse operation and the associated chip temperature responses also deserve examination. In accordance with the analogy to electrical systems, the chip temperature response can be viewed

like a voltage increase across an

RC section which is being fed by a current pulse generator. The following relationship applies: $V_{(t)} = R \cdot I \cdot (1 - e^{t/R \cdot C})$ and for the increase in temperature: $T_{(t)} = R_{th} \cdot P \cdot (1 - e^{t/R_{th} \cdot C_{th}})$

This heating-up and cooling-down process is presented qualitatively in **Figure 8** (valid for $t_p >> 2$ ms only).

The chip temperature goes up and down between T_{min} and T_{max} . The variation depends on the magnitude of the power pulse and its duty cycle.



Figure 8 Chip Temperature T_j vs. Time, for Periodic Pulse Operation

This junction temperature transients can be represented in the form of a function if the dynamic thermal impedance $Z_{th} = (T_{max} - T_{min}) / P_V$ is shown versus pulse width t_p for different duty cycles (duty cycle = $DC = t_p/T$) (**Figure 9**). A special case of this representation is the dynamic thermal impedance in single-pulse operation (DC = 0). **Figure 10** shows the thermal impedance in single-pulse operation for the medium-power package P-DSO-14-4 for three different cooling areas on the PCB. This function clearly shows the regions of dominance of the various time constants of the chip, the lead frame, and the PCB.

The chip time constant t_D lies in the millisecond range, whereas the lead frame dominates in the range of several 100 ms and the PCB in the 100-second range.









Finite Element Method (FEM)

The steps of the Finite Element Method (FEM) are explained below and one example is provided per group. The geometric data of the package is entered into the FEM model to calculate the thermal resistance. This avoids timeconsuming measurements. **Figure 11** shows an implemented model.



P-TO252-3-1

bond are by to spot

P-DSO-14-4

Figure 11 FEM Model of Heat Sink and Thermal Enhanced Package

The temperatures of the individual components (chip, diepad, molding compound, and leadframe) can be viewed individually or in combination (**Figure 12**).



Chip with two active areas (dice only)



Mold compound without cooling tab, chip and lead frame



P-TO252-3-1 without mold compound with P_V = 3 W for determining the $R_{\text{thi-c}}$



Chip and lead frame of the SOT223-4-2 package on a PCB with heat sink





Lead frame of the SCT595-5-1 on a PCB with heat sink



SOT223-4-2 on a PCB with 6 cm² heat sink; $R_{\rm thj-a} \sim$ 70 K/W is calculated at $P_{\rm V}$ = 0.5 W

Three different PCBs have been created for each package model. They differ in the size of the copper laminated area A (heat sink) which is linked to the heat dissipating parts of the case (diepad in the P-TO252-3-1 or center pins in the P-DSO-14) (**Figure 13**).







Application-Board for R_{th} Measurement R_{th}-P-DSO-14-4 LP 1.0



Application-Board for R_{th} Measurement R_{th}-P-TO252-3-1 LP 1.1

Figure 13 PCB-Layout for FEM-Simulation P-DSO-14-4 and P-TO252-3-1

Determining the Static Heat Resistance

The FEM simulation calculates the thermal static resistance R_{thj-a} (junction-ambient) and the R_{thj-c} (junction-case) for packages with enhanced die-pad or $R_{thj-pin}$ (junction to a defined pin) for thermal enhanced P-DSO packages without die-pad. This value depends only slightly on the active chip area. It is sufficient to simulate just one medium-sized chip (>2 mm²). If the static thermal resistance R_{thj-a} is applied versus the PCB heat sink area, a very important function is obtained for the application of the component. By estimating the heat sink area in a real application, the user can easily determine the expected R_{thj-a} , especially as the simulated values are calculated in still air. Therefore, they represent the "worst case". In real applications the values for the heat resistance are much lower. At an air stream of 500 lin ft/min (linear feet per minute) the R_{thj-a} of the P-DSO-14-4 for example is up to 15 % lower (**Figure 15**).







Figure 15 Thermal Resistance Junction to Ambient $R_{\text{thj-a}}$ vs. Airspeed for the P-DSO-14-4 and P-TO252-3-1 Packages

Measuring the $R_{\text{thj-a}}$ in a Real Application:

Using the measurement described below the real thermal resistance can be determined. To determine the actual R_{thj-a} the temperature difference between chip temperature T_j and ambient temperature T_a is required. The

equation
$$R_{\text{thj-a}} = \frac{T_{\text{j}} - T_{\text{a}}}{P_{\text{V}}}$$
 applies.

The power loss P_V and the ambient temperature T_a can be determined easily in a temperature chamber or calculated.

To measure the chip temperature (T_i) requires a little trick:

A temperature sensor is required on the chip which can also be read during operation. In many products a substrate diode can be used at an output (Status, Reset, etc.) to measure the chip temperature. To do this, the forward voltage V_F of the diode is measured at load independent current as a calibration curve. Due to the characteristic temperature behavior of the forward voltage - it has a negative temperature coefficient of approx. -2 mV/K - the relevant chip temperature can be determined. The calibration curve is measured in the temperature chamber with airflow. The power loss should be kept as low as possible to ensure the chip temperature remains equal to the ambient temperature. For the voltage regulator TLE 4269 GM (P-DSO-14-4 Package) a calibration curve (measured at the diode at the reset output, pin 7). RO is illustrated in **Figure 16**. **Figure 17** shows the corresponding measuring circuit.



Figure 16 Calibration Curve TLE 4269 GM for I_{RO} = -500 µA (current drawn from Pin 7; RO)

The $R_{\text{thj-a}}$ of any application can be determined by measuring the forward voltage of an output with substrate diode during operation (**Figure 17**).

When the switch S1 is closed and the output voltage $V_{Q} = 5$ V, the output current is $\frac{5}{35}$ A.

The power loss $P_V = (V_1 - V_0) \bullet I_0$ in the chip of the voltage regulator is now 1 W. Now, change the ambient temperature T_a and measure the respective forward voltage $V_{\rm F}$ of the diode. The appropriate $T_{\rm j}$ for every $V_{\rm F}$ value can be read from the calibration curve $V_{\rm F} = f(T_{\rm j})$.

The exact heat resistance of the real application is calculated with this values in the formula

$$R_{\text{thj-a}} = \frac{T_{\text{j}} - T_{\text{a}}}{P_{\text{V}}}$$

Parameters such as air flow can be changed without affecting the measuring accuracy.



1. Measurement of function $V_F = I(I_a)$: S_1 open; we get $I_Q = 0$ mA and $P_V = V_I * I_I \sim 0$ mW $T_a \sim T_j$



 P_{V} = Power losses T_{a} = Ambient temperature T_{i} = Junction temperature

Figure 17 Measuring Circuit with TLE 4269GM

Determining the Dynamic Heat Resistance

The FEM analysis is used also for dynamic processes. As described above, the dynamic thermal impedance is defined as the ratio of the temperature difference $\Delta T = T_j - T_a$ (chip temperature - start temperature) after the time t_p to the power loss. If a transient FEM simulation is performed, it is easy to obtain the graph $Z_{thj-a} = f(t_p)$ (dynamic thermal impedance as a function of the pulse width t_p). For the P-TO252-3-1 (D-Pack) and the P-DSO-14-4 the thermal impedances for the abovementioned PCB configurations are specified (**Figure 18**). The peak temperatures can be

calculated easily from these curves:

- P-TO252-3-1 (D-Pack)
- 3 cm² heat sink
- Power loss $P_{\rm V}$ = 10 W
- Pulse width $t_{\rm p}$ = 200 ms
- Ambient temperature $T_a = 85 \text{ °C}.$

From the middle curve (**Figure 18**), the $Z_{\text{thj-a}}$ of approximately 3.5 K/W at $t_p = 200$ ms gives a temperature rise $\Delta T = P_V \times Z_{\text{thj-a}}$ of 35 K and finally a peak temperature T_{imax} of 85 °C+35 °C = 120 °C.





Figure 18 Thermal Impedance Junction to Ambient Z_{thj-a} vs. Single Pulse Time t_p

Summary

For each case listed in Table 1, a "Package and Thermal Information" data sheet is provided in the appendix.Each data sheet shows the footprint and case dimensions. The various versions of the PCBs used for the simulation are shown. It shows the heat distribution diagrams and the result diagrams of the FEM simulation. The left side shows the diagram of the static thermal resistance R_{thi-a} depending on the PCB heat sink area A. It includes the related thermal resistance $R_{\text{thi-c}}$ (junction-case) or $R_{\text{thi-pin}}$.

On the right side is the diagram for the dynamic heat resistance $Z_{\text{thi-a}}$, with three graphs for the various PCB heat sinks depending on the single pulse duration $t_{\rm p}$. This information is a valuable aid for SMD Power applications. It is intentionally limited to PCBs laminated on one side because it represents the cost optimum. For double sided PCBs or multilayers a simple attempt with conductance cross sections can be made to determine the change in the PCB thermal resistance (compare thermal data sheet of

P-DSO-20-10 with P-DSO-36-10 in the appendix).

The PCBs are usually installed in closed plastic cases. The most favorable heat path then usually forms at plug contacts to the cables because a supply wire with an adequate cross section is ideal as a heat conductor. The future of chip placement requires mechatronic solutions where the PCB can be replaced by chip-connector-supply wire configurations.

Package and Thermal Information Appendix

	P-DS0-8-1	22
Sanna .	P-DS0-14-4	23
	P-DS0-16-1	24
	P-DS0-20-1	25
Caller and	P-DS0-20-6	26
	P-DS0-24-3	27
	P-DS0-28-6	28
	P-DS0-20-10	29
	P-DS0-36-10	30
A.	SCT595-5-1	31
	SOT223-4-2	32
	P-T0252-3-1	33
	P-T0263-5-1	34





PC-Board Application-Boards for R_{th} - Measurement P-DSO-8-1 P-DSO-8-1 P-DSO-8-1 Infineon Infineon Infineon a/2 2 3 cm² 1 6 cm² 3 Footprint only 0.67 0.67 FR4; 80 x 80 x 1.5 mm; 35 μ Cu, 5 μ Sn FR4; 80 x 80 x 1.5 mm; 35 μ Cu, 5 μ Sn FR4; 80 x 80 x 1.5 mm; 35 μ Cu, 5 μ Sn A = 600 mm²; a = 17.32 mm A = 300 mm²; a = 12.247 mm Footprint only







Package and Thermal Information



P-DSO-14-4







Application-Boards for R_{th} - Measurement



A = 300 mm²; a = 12.247 mm



FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 1 \text{ W}$; zero airflow) **Finite Element Method** A = 300 mm²; T_a = 298 K; T_{max} = 389.8 K A = 600 mm²; T_a = 298.1 K; T_{max} = 377.7 K

10⁻²

10⁻¹

100





10

s 10³

10 $\blacktriangleright t_{\rm p}$









Footprint only; $T_a = 298$ K; $T_{max} = 419.1$ K



Package and Thermal Information



P-DSO-20-1



Application-Board for R_{th} - Measurement















FR4; 80 x 80 x 1.5 mm; 35 µ Cu, 5 µ Sn FR4; 80 x 80 x 1.5 mm; 35 µ Cu, 5 µ Sn Footprint only

-24-3 -28-6



Diagrams











FR4; $80 \times 80 \times 1.5$ mm; 35μ Cu, 5μ Sr A = 300 mm²; a = 12.247 mm









PC-Board





Application-Boards for $R_{\rm th}$ - Measurement





Finite Element Method FEM Simulation (chip area $\ge 2 \text{ mm}^2$; $P_v = 1 \text{ W}$; zero airflow)















 $A = 300 \text{ mm}^2$; a = 12.247 mm



FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Finite Element MethodImage: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Finite Element MethodImage: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ mm}$









PC-Board

Application-Boards for R_{th} - Measurement





A = 300 mm²; 16 x 19 mm

Finite Element Method FEM Simulation (chip area $\ge 2 \text{ mm}^2$; $P_v = 3.5 \text{ W}$; zero airflow) A = 600 mm²; T_a = 298 K; T_{max} = 398 K





A = 300 mm²; T_a = 298 K; T_{max} = 427 K



Package and Thermal Information



SCT595-5-1







Application-Boards for R_{th} - Measurement





FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Finite Element MethodImage: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Finite Element MethodImage: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ W}$; zero airflow)Image: Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 0.2 \text{ mm}^2$; $P_v = 0.$







SOT223-4-2



SOT223

----Footprint

10

s 10³

102

► t_p

300 mm²

600 mm²

10⁰







Package and Thermal Information



P-T0252-3-1 Footprint/Dimensions



FR4; 80 x 80 x 1.5 mm; 35 µ Cu, 5 µ Sn A = 600 mm²; a = 24.49 mm



A = 300 mm²; a = 17.32 mm





A = 600 mm²; T_a = 298 K; T_{max} = 353 K



A = 300 mm²; T_a = 298 K; T_{max} = 376 K















Finite Element Wethod FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ VV}$; zero airflow) FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ VV}$; zero airflow) $\int_{A = 600 \text{ mm}^2$; $T_a = 298 \text{ K}$; $T_{max} = 417 \text{ K}$ FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ VV}$; zero airflow) FEM Simulation (chip area $\geq 2 \text{ mm}^2$; $P_v = 3 \text{ VV}$; zero airflow) $\int_{A = 300 \text{ mm}^2$; $T_a = 298 \text{ K}$; $T_{max} = 455 \text{ K}$ Figure 4.5 K



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